

DOSEMI

IGBT

DG75A12TCFS

1200V/75A IGBT with Diode

General Description

DOSEMI IGBT Power Discrete provides ultra low conduction loss as well as low switching loss. They are designed for the applications such as solar power.

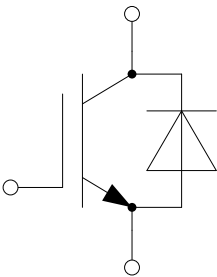
Features

- Low $V_{CE(sat)}$ Fast IGBT technology
- Low switching loss
- Maximum junction temperature 175°C
- $V_{CE(sat)}$ with positive temperature coefficient
- Fast & soft reverse recovery anti-parallel FWD

Typical Applications

- Solar power
- UPS
- 3-level-application

Equivalent Circuit Schematic



Type	Package	Marking	Shipping
DG75A12TCFS	TO-247PLUS-3L	DG75A12TCFS	30Units/Tube

Absolute Maximum Ratings $T_C=25^{\circ}\text{C}$ unless otherwise noted**IGBT**

Symbol	Description	Value	Unit
V_{CES}	Collector-Emitter Voltage	1200	V
V_{GES}	Gate-Emitter Voltage	± 20	V
I_C	Collector Current @ $T_C=25^{\circ}\text{C}$ @ $T_C=120^{\circ}\text{C}$	150 75	A
I_{CM}	Pulsed Collector Current t_p limited by T_{vjmax}	225	A
P_D	Maximum Power Dissipation @ $T_{vj}=175^{\circ}\text{C}$	555	W

Diode

Symbol	Description	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	1200	V
I_F	Diode Continuous Forward Current @ $T_C=25^{\circ}\text{C}$ @ $T_C=100^{\circ}\text{C}$	141 75	A
I_{FM}	Diode Pulsed Current t_p limited by T_{vjmax}	225	A

Discrete

Symbol	Description	Values	Unit
T_{vjop}	Operating Junction Temperature	-40 to +175	$^{\circ}\text{C}$
T_{STG}	Storage Temperature Range	-55 to +150	$^{\circ}\text{C}$
T_S	Soldering Temperature, 1.6mm from case for 10s	260	$^{\circ}\text{C}$

IGBT Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{CE(sat)}$	Collector to Emitter Saturation Voltage	$I_C=75\text{A}, V_{GE}=15\text{V}, T_{vj}=25^{\circ}\text{C}$		1.50	1.95	V
		$I_C=75\text{A}, V_{GE}=15\text{V}, T_{vj}=150^{\circ}\text{C}$		1.95		
		$I_C=75\text{A}, V_{GE}=15\text{V}, T_{vj}=175^{\circ}\text{C}$		2.05		
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	$I_C=1.5\text{mA}, V_{CE}=V_{GE}, T_{vj}=25^{\circ}\text{C}$	4.0	4.8	5.5	V
I_{CES}	Collector Cut-Off Current	$V_{CE}=V_{CES}, V_{GE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$			200	μA
I_{GES}	Gate-Emitter Leakage Current	$V_{GE}=V_{GES}, V_{CE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$			100	nA
R_{Gint}	Internal Gate Resistance			0		Ω
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, f=100\text{kHz}, V_{GE}=0\text{V}$		5.10		nF
C_{oes}	Output Capacitance			0.12		nF
C_{res}	Reverse Transfer Capacitance			0.02		nF
Q_G	Gate Charge	$V_{GE}=-15\dots+15\text{V}$		0.31		μC
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=600\text{V}, I_C=75\text{A}, R_G=4.7\Omega, L_S=40\text{nH}, V_{GE}=\pm 15\text{V}, T_{vj}=25^{\circ}\text{C}$		33		ns
t_r	Rise Time			59		ns
$t_{d(off)}$	Turn-Off Delay Time			146		ns
t_f	Fall Time			60		ns
E_{on}	Turn-On Switching Loss			8.21		mJ
E_{off}	Turn-Off Switching Loss			2.85		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=600\text{V}, I_C=75\text{A}, R_G=4.7\Omega, L_S=40\text{nH}, V_{GE}=\pm 15\text{V}, T_{vj}=150^{\circ}\text{C}$		35		ns
t_r	Rise Time			60		ns
$t_{d(off)}$	Turn-Off Delay Time			186		ns
t_f	Fall Time			106		ns
E_{on}	Turn-On Switching Loss			10.8		mJ
E_{off}	Turn-Off Switching Loss			4.21		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=600\text{V}, I_C=75\text{A}, R_G=4.7\Omega, L_S=40\text{nH}, V_{GE}=\pm 15\text{V}, T_{vj}=175^{\circ}\text{C}$		36		ns
t_r	Rise Time			60		ns
$t_{d(off)}$	Turn-Off Delay Time			192		ns
t_f	Fall Time			109		ns
E_{on}	Turn-On Switching Loss			11.2		mJ
E_{off}	Turn-Off Switching Loss			4.35		mJ

Diode Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_F	Diode Forward Voltage	$I_F=75\text{A}, V_{GE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$		1.70	2.15	V
		$I_F=75\text{A}, V_{GE}=0\text{V}, T_{vj}=150^{\circ}\text{C}$		1.70		
		$I_F=75\text{A}, V_{GE}=0\text{V}, T_{vj}=175^{\circ}\text{C}$		1.65		
Q_r	Recovered Charge	$V_R=600\text{V}, I_F=75\text{A},$ $-di/dt=880\text{A}/\mu\text{s}, L_s=40\text{nH},$ $V_{GE}=-15\text{V}, T_{vj}=25^{\circ}\text{C}$		5.69		μC
t_{rr}	Recovered Time			149		ns
I_{RM}	Peak Reverse Recovery Current			63		A
E_{rec}	Reverse Recovery Energy			1.24		mJ
Q_r	Recovered Charge	$V_R=600\text{V}, I_F=75\text{A},$ $-di/dt=870\text{A}/\mu\text{s}, L_s=40\text{nH},$ $V_{GE}=-15\text{V}, T_{vj}=150^{\circ}\text{C}$		11.0		μC
t_{rr}	Recovered Time			248		ns
I_{RM}	Peak Reverse Recovery Current			78		A
E_{rec}	Reverse Recovery Energy			3.04		mJ
Q_r	Recovered Charge	$V_R=600\text{V}, I_F=75\text{A},$ $-di/dt=870\text{A}/\mu\text{s}, L_s=40\text{nH},$ $V_{GE}=-15\text{V}, T_{vj}=175^{\circ}\text{C}$		12.4		μC
t_{rr}	Recovered Time			269		ns
I_{RM}	Peak Reverse Recovery Current			83		A
E_{rec}	Reverse Recovery Energy			3.53		mJ

Discrete Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Min.	Typ.	Max.	Unit
R_{thJC}	Junction-to-Case (per IGBT)			0.270	K/W
	Junction-to-Case (per Diode)			0.392	
R_{thJA}	Junction-to-Ambient		40		K/W

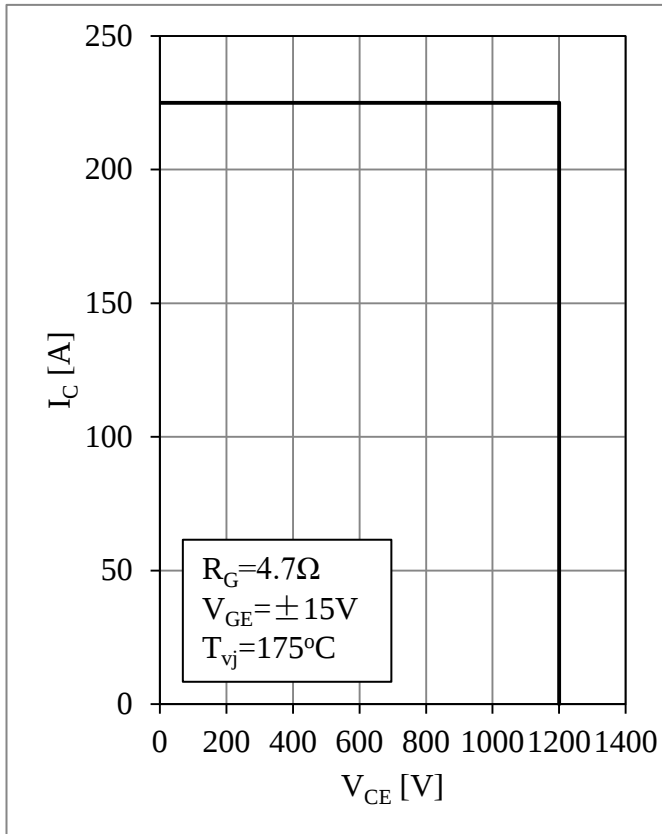


Fig 1. RBSOA

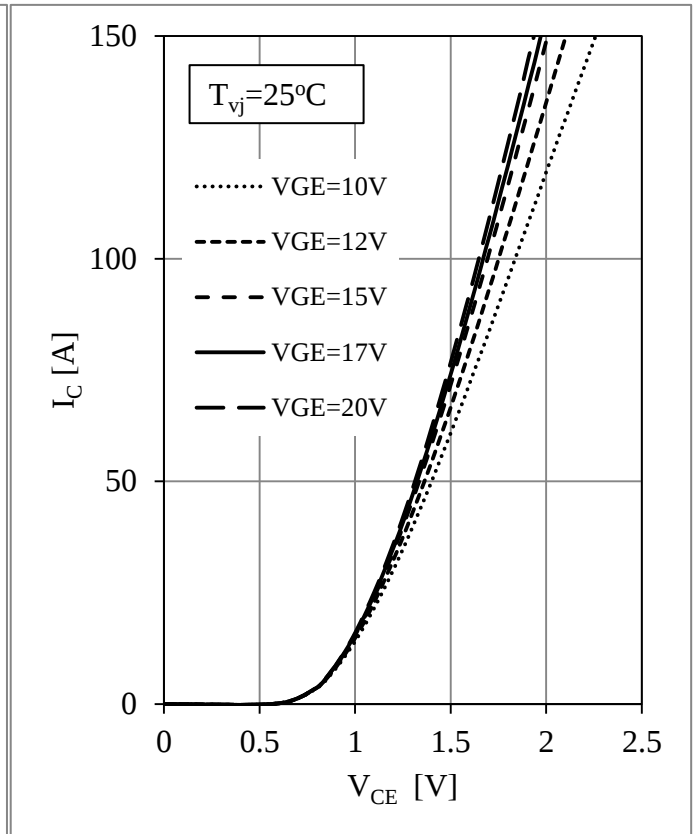


Fig 2. IGBT Output Characteristics

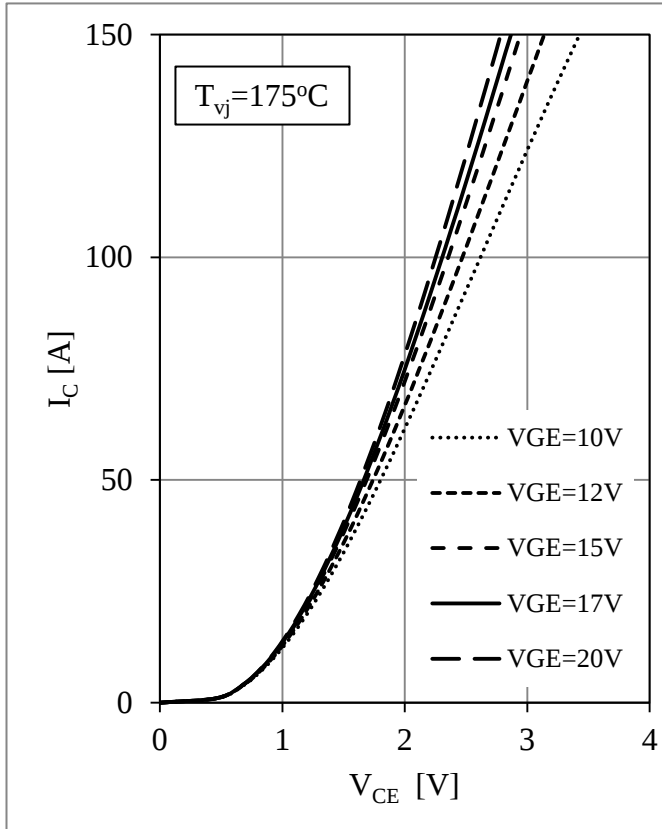


Fig 3. IGBT Output Characteristics

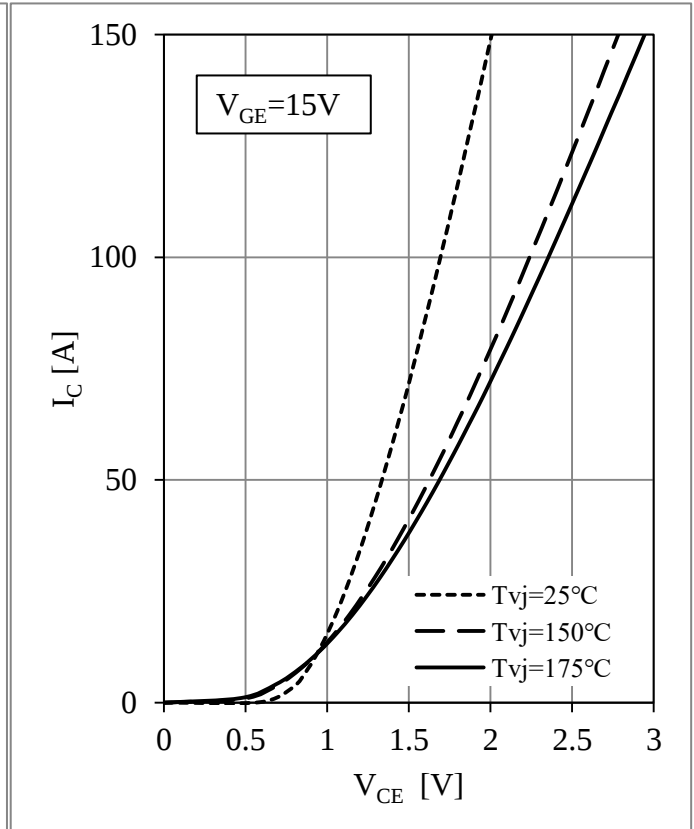


Fig 4. IGBT Output Characteristics

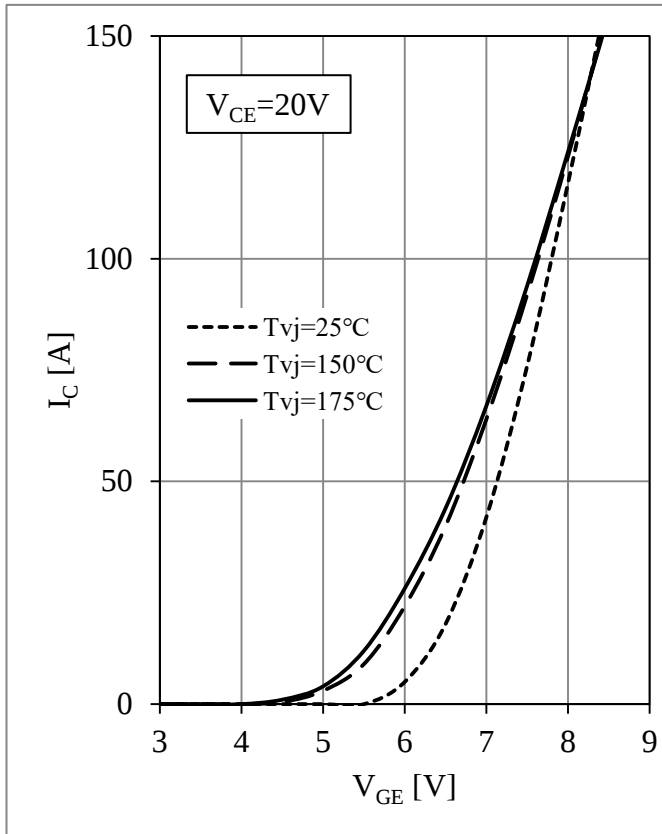
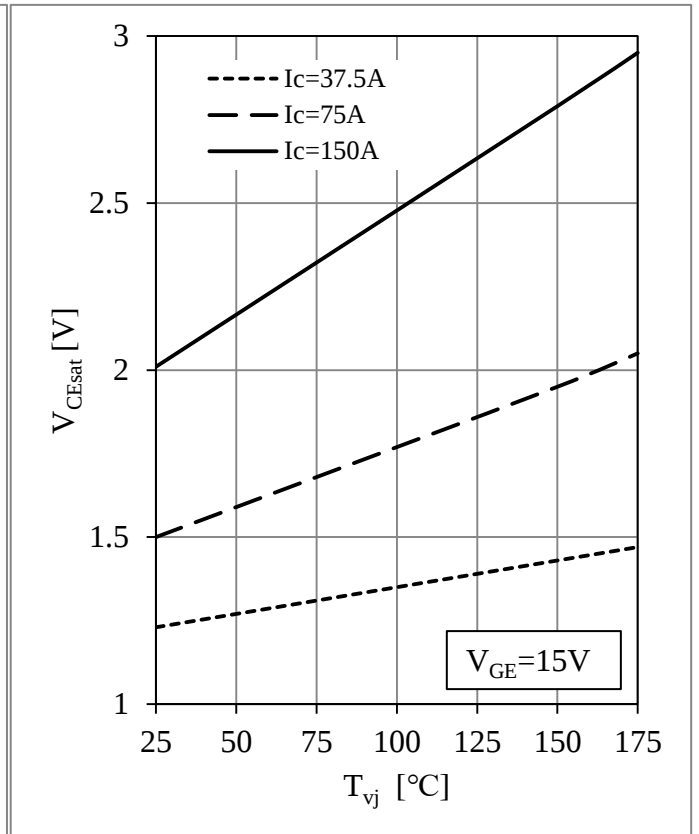
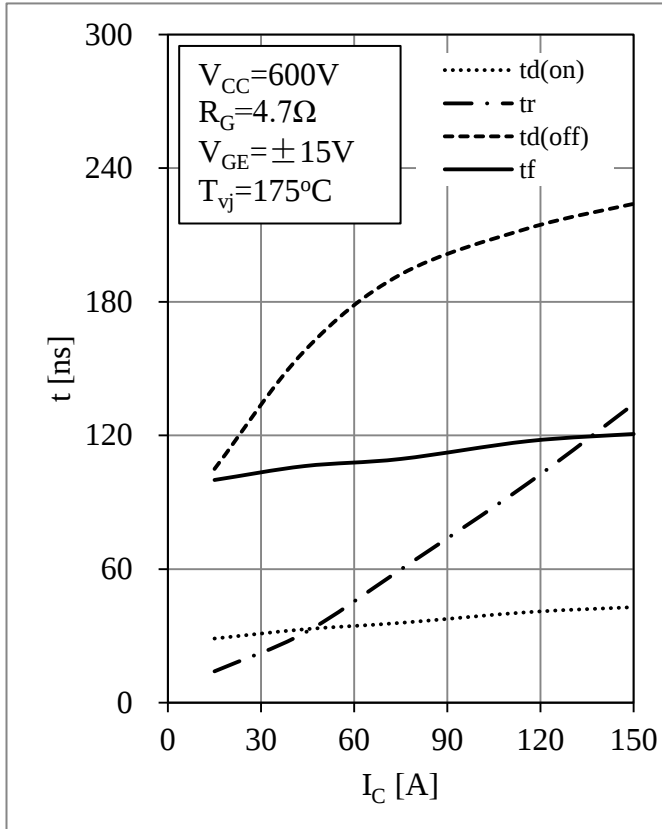
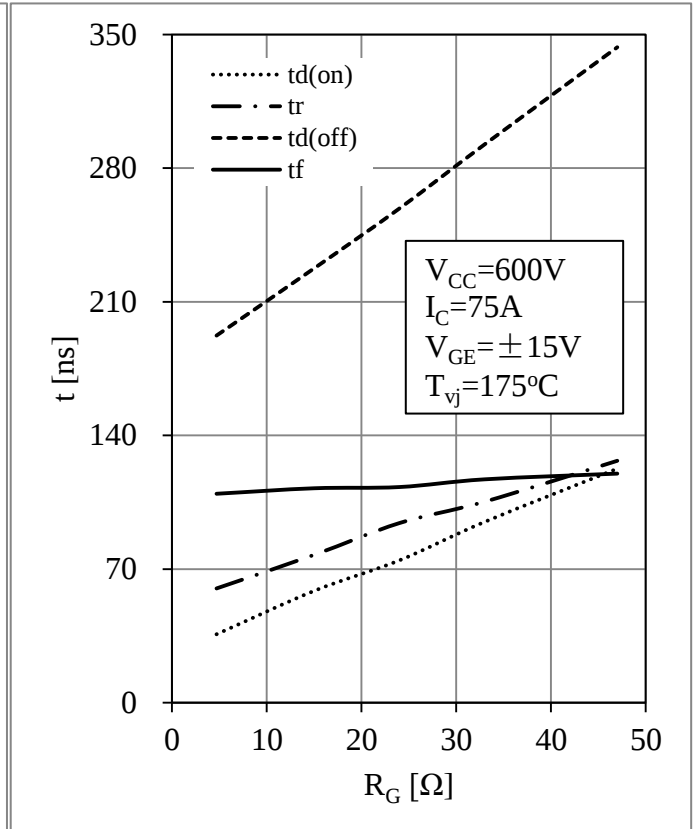
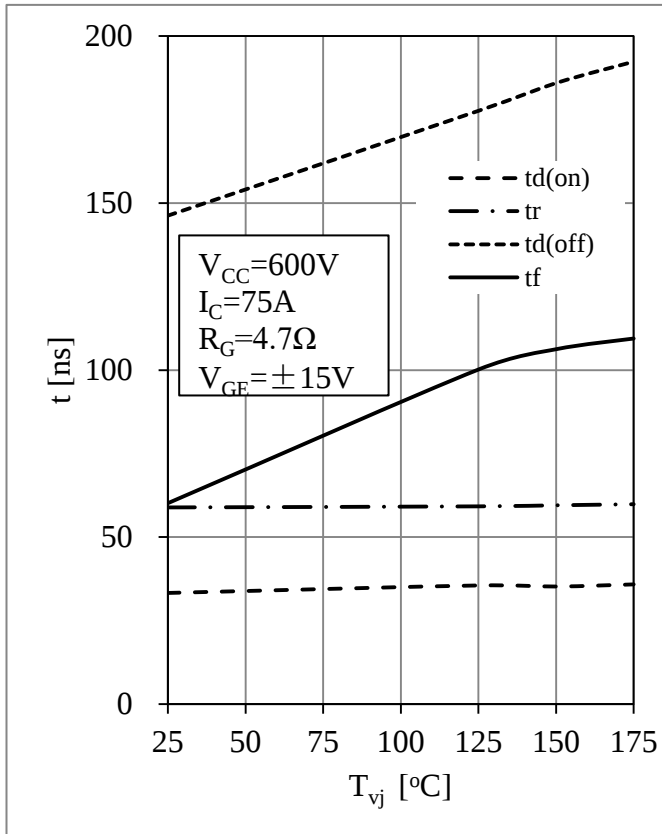
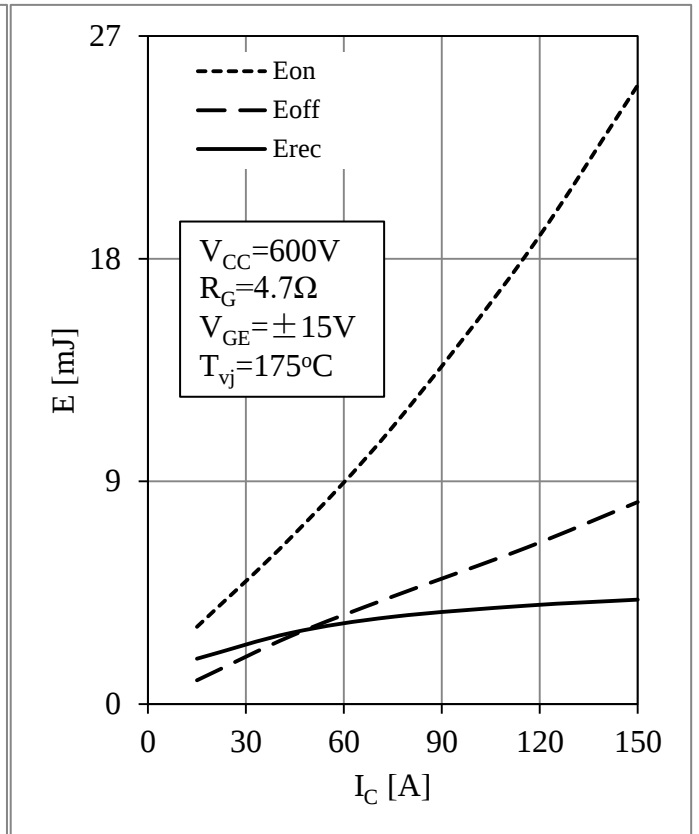
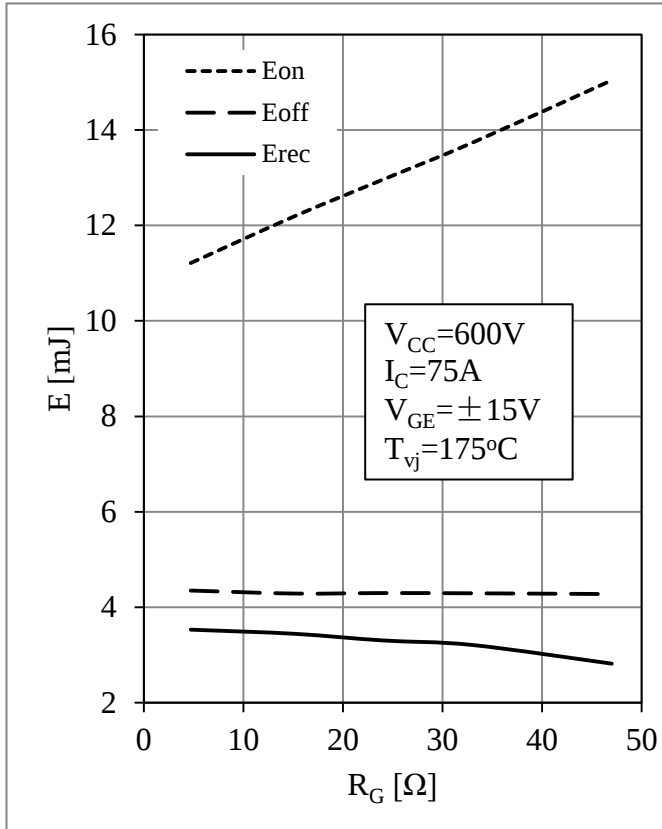
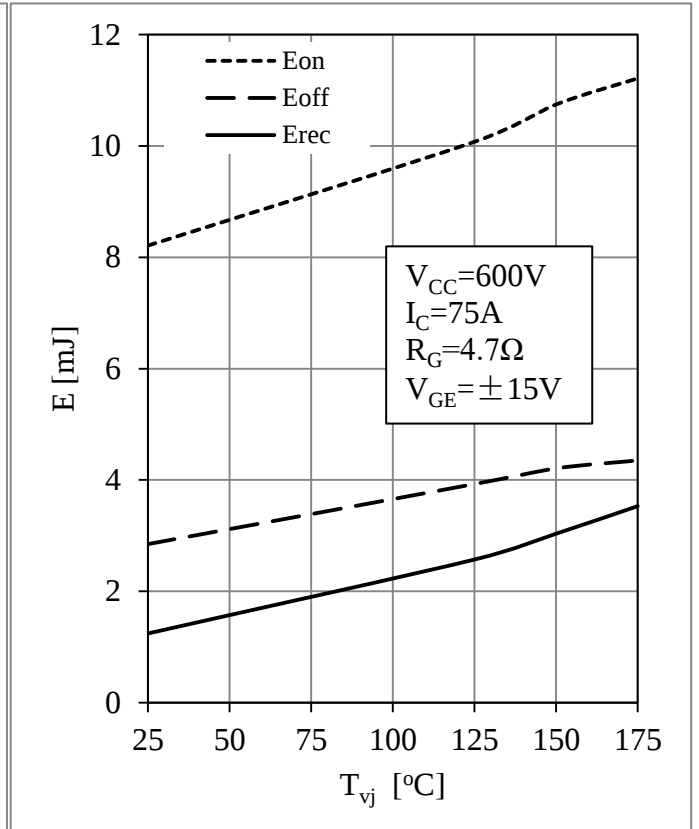
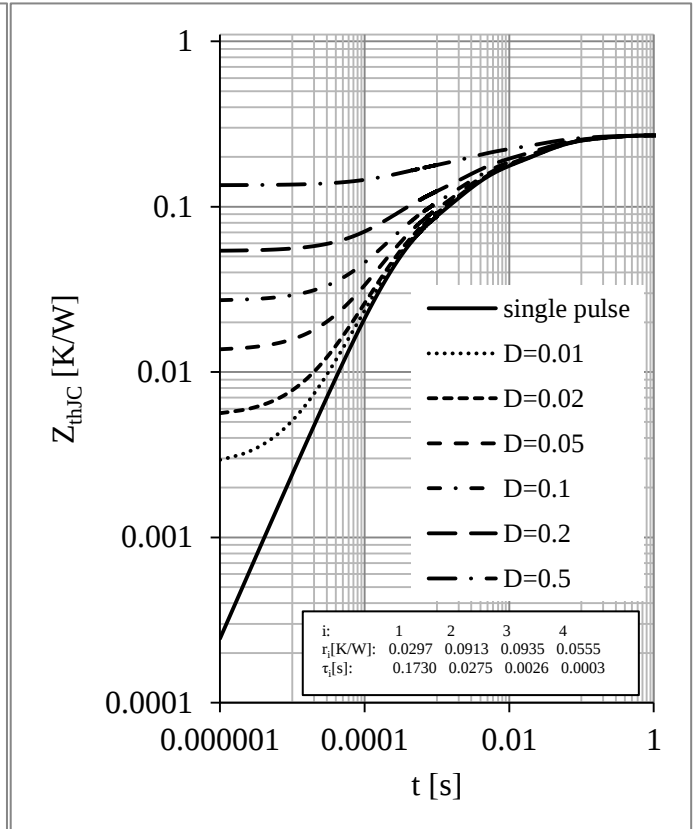
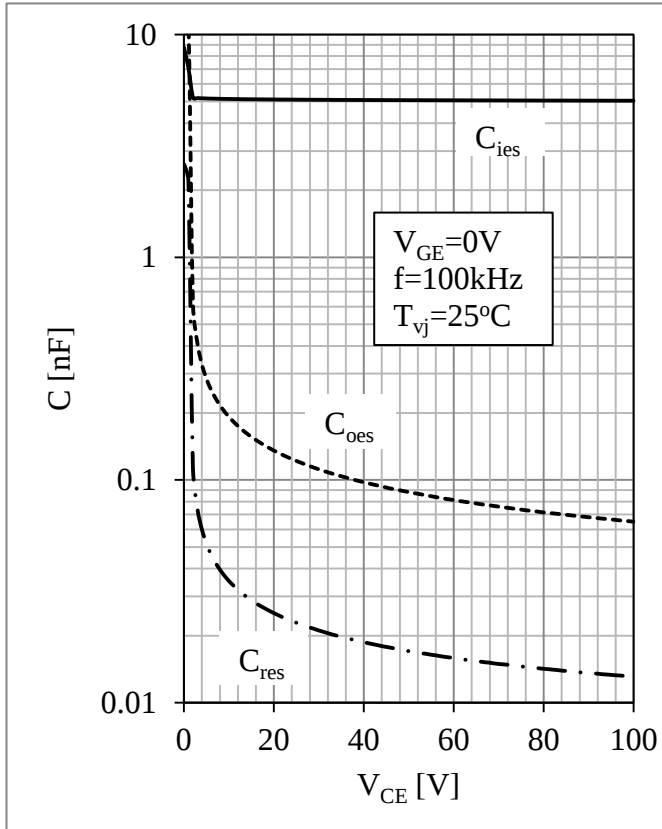
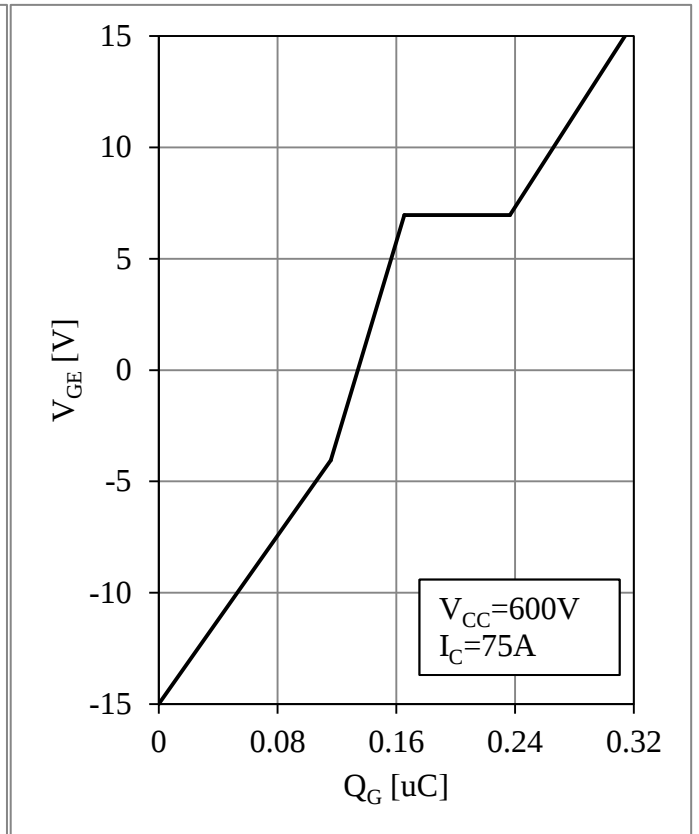
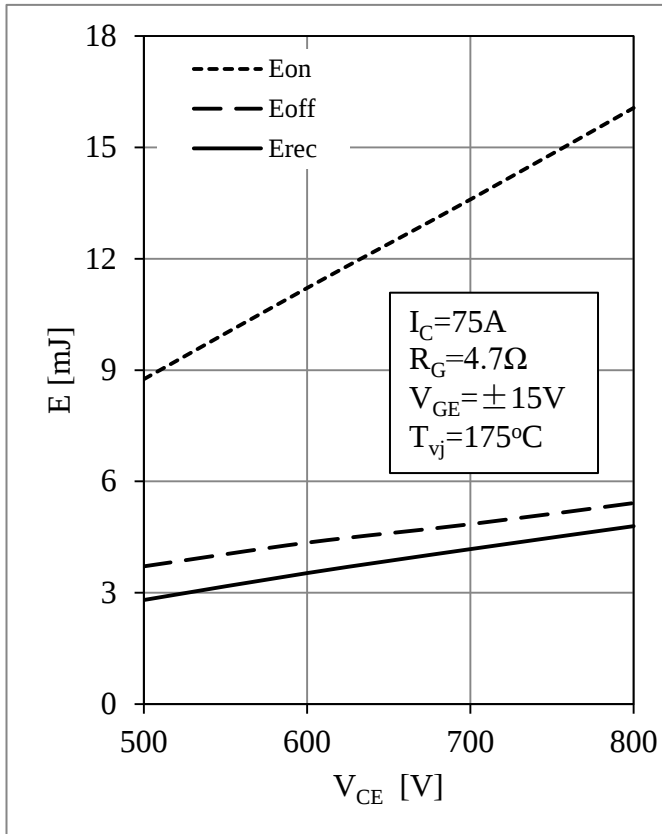


Fig 5. IGBT Transfer Characteristics

Fig 6. Collector-emitter saturation voltage vs T_{vj} Fig 7. IGBT Switching Times vs. I_C Fig 8. IGBT Switching Times vs. R_G

Fig 9. IGBT Switching Times vs. T_{vj} Fig 10. Switching Energy Loss vs. I_C Fig 11. Switching Energy Loss vs. R_G Fig 12. Switching Energy Loss vs. T_{vj}



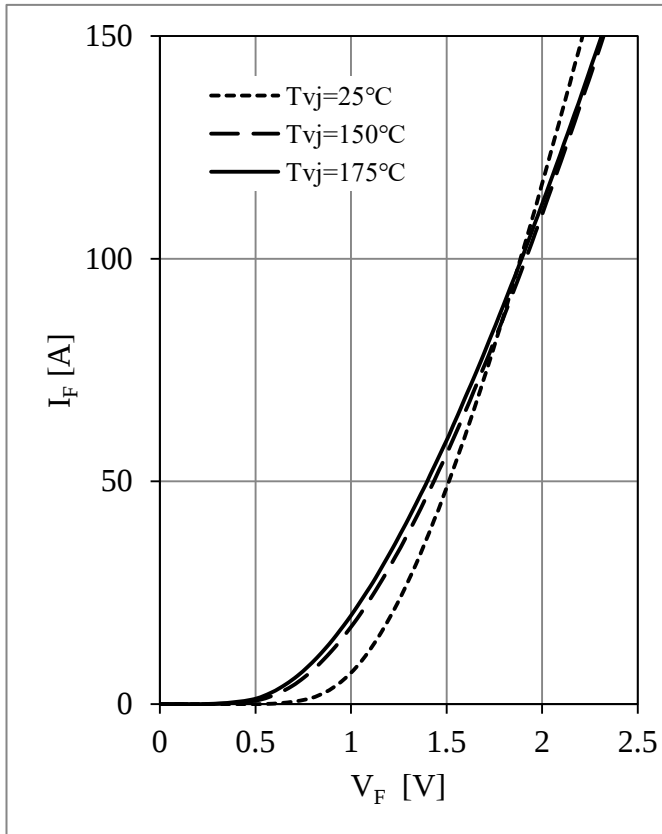
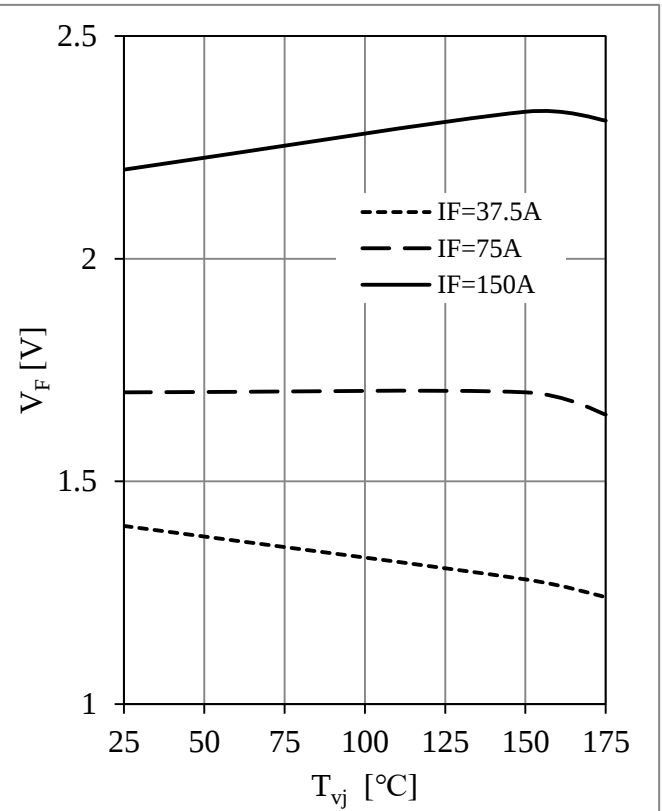
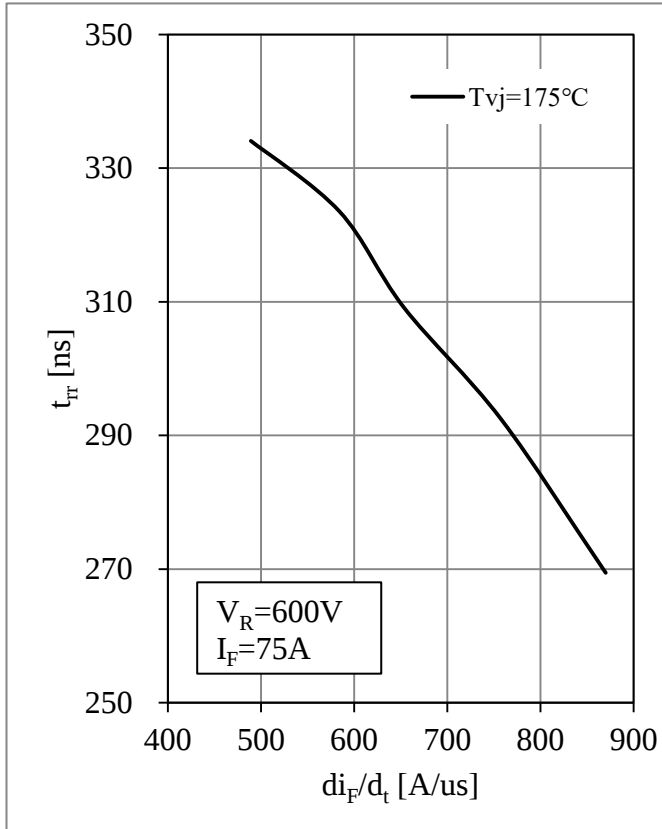
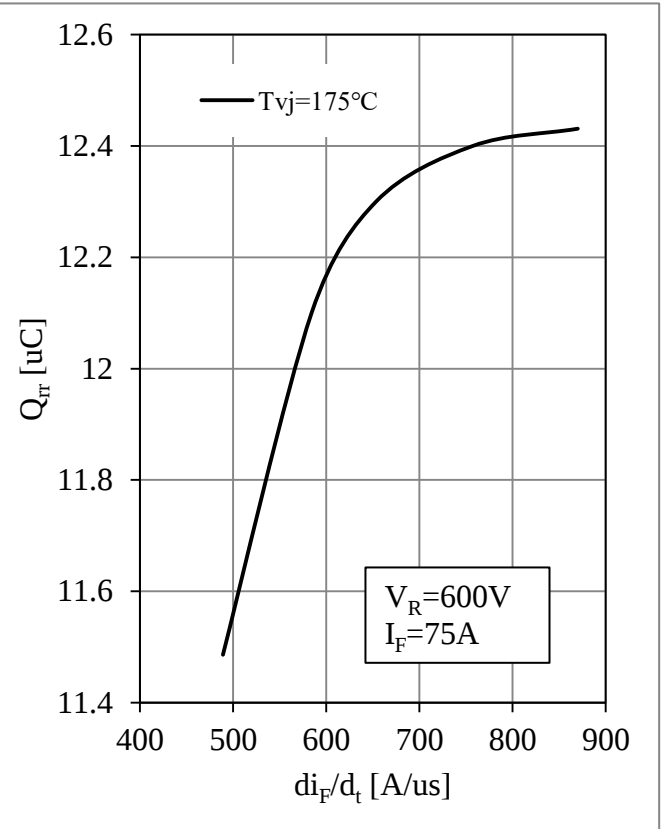


Fig 17. Diode Forward Characteristics

Fig 18. Diode Forward Voltage Vs T_{vj} Fig 19. Reverse Recovery Time vs. di_F/dt Fig 20. Reverse Recovery Charge vs. di_F/dt

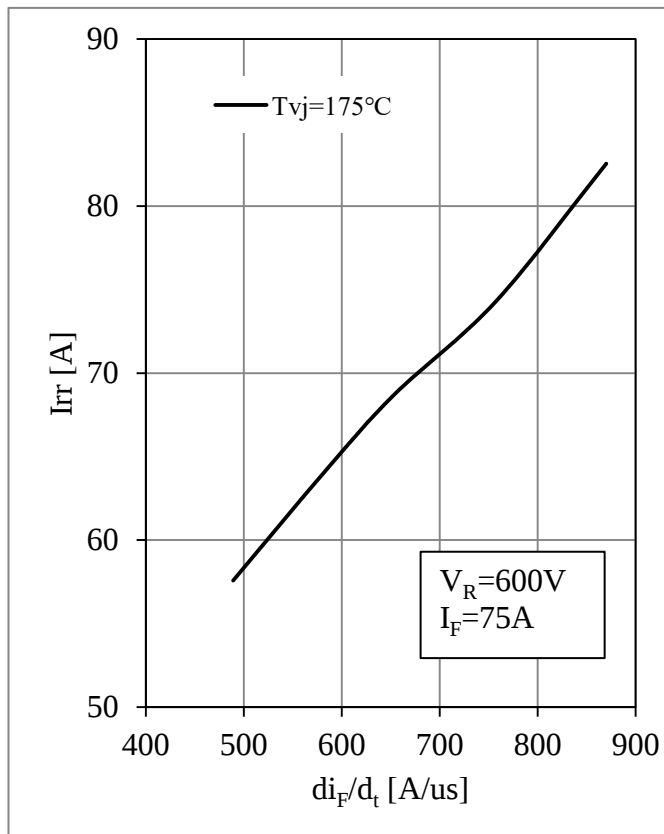
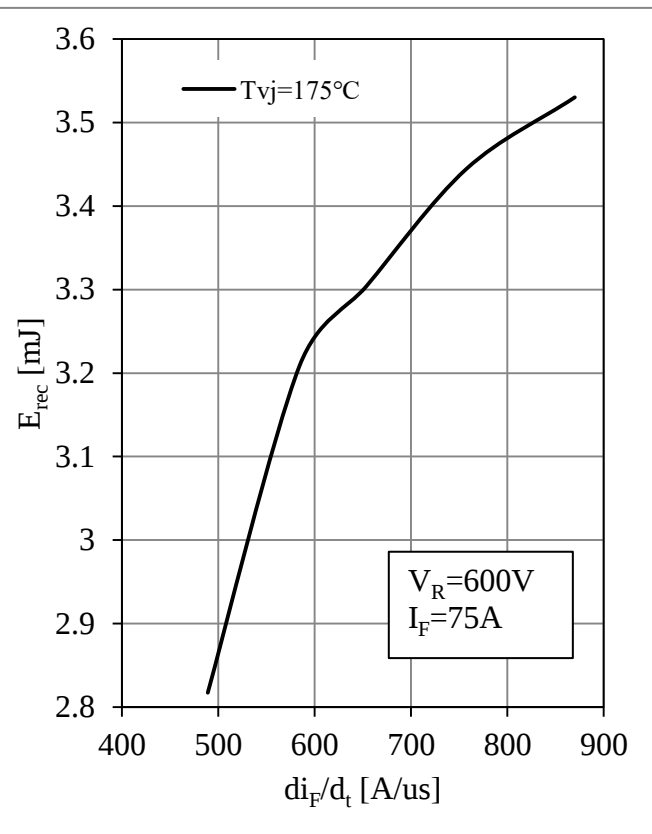
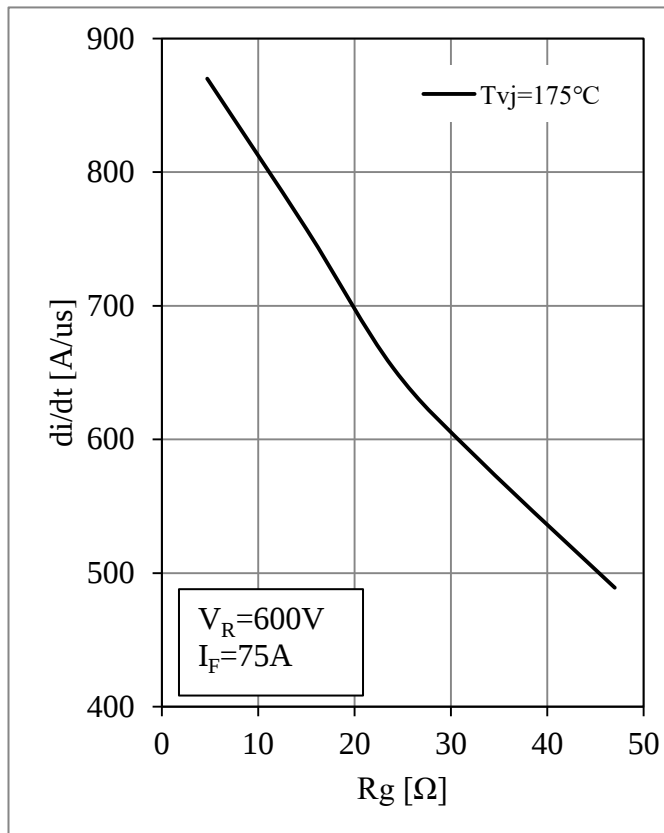
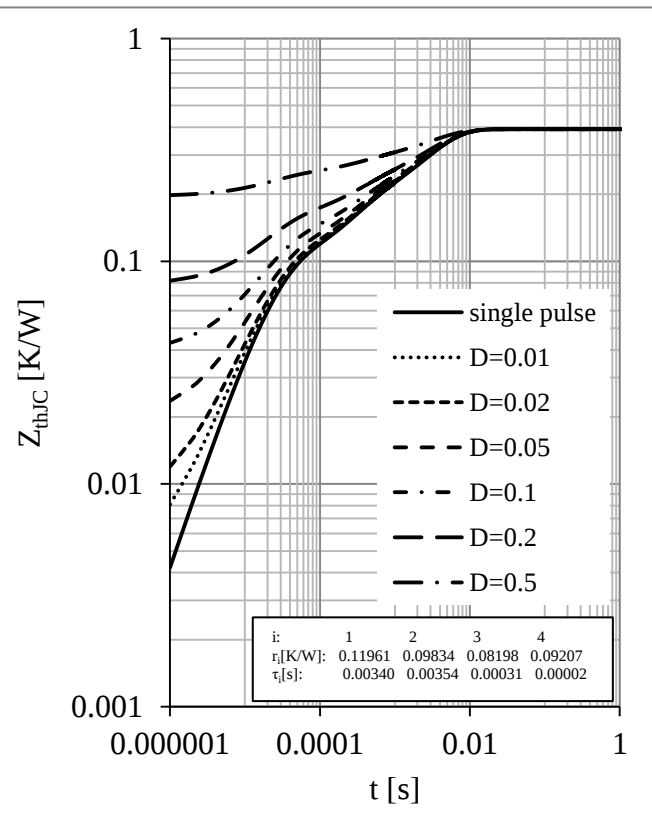
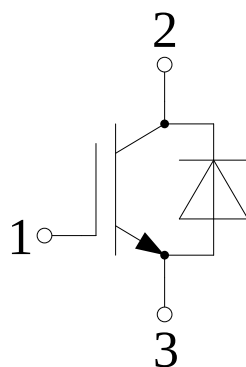
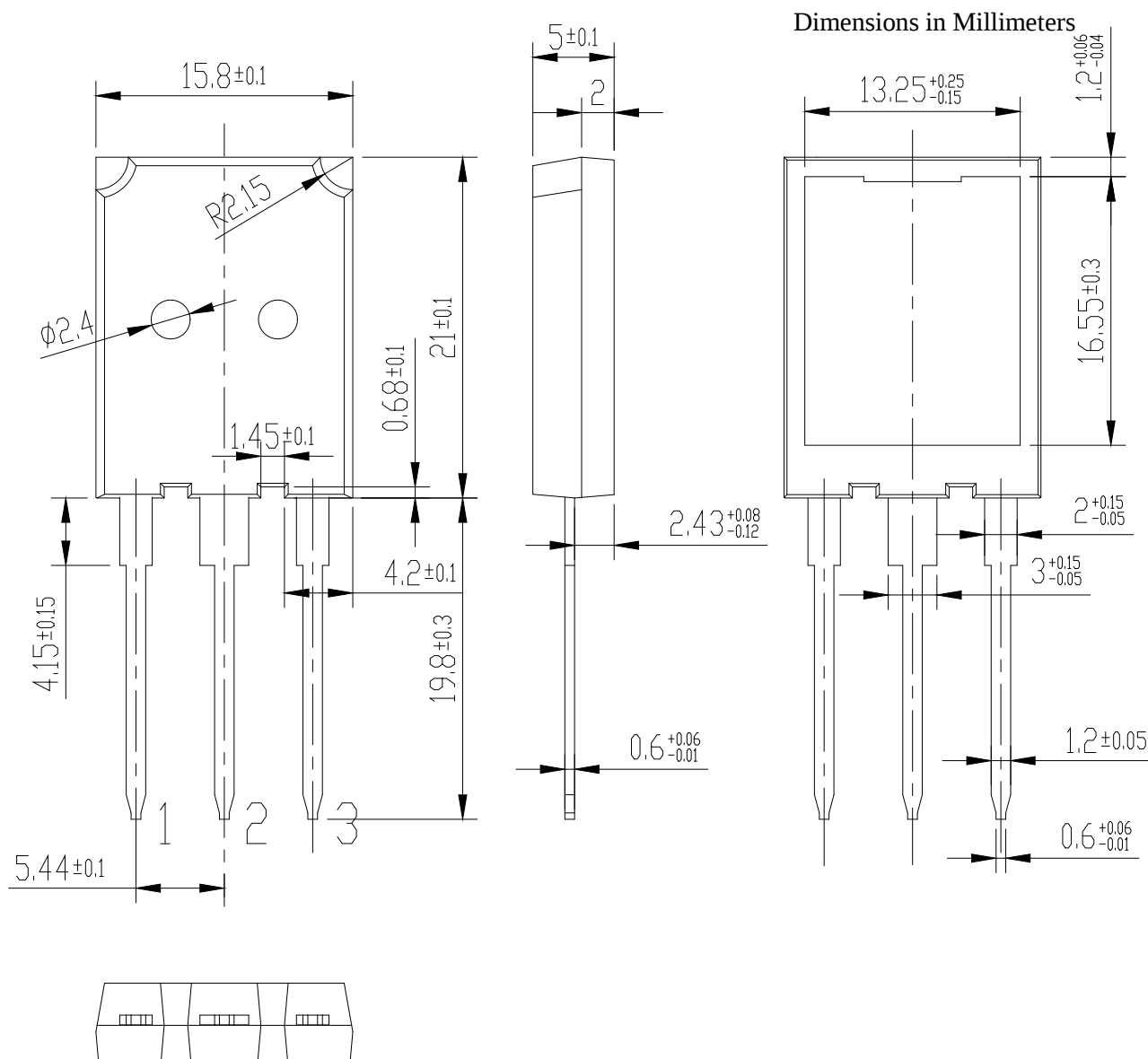
Fig 21. Reverse Recovery Current vs. di_F/dt Fig 22. Reverse Energy Losses vs. di_F/dt Fig 23. di_F/dt vs R_g 

Fig 24. Diode Transient Thermal Impedance

Circuit Schematic



Package Dimensions



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